

Notice of References Cited		Application/Control No. 10/814,729	Applicant(s)/Patent Under Reexamination NGUYEN ET AL.	
		Examiner Xavier Szewai Wong	Art Unit 2416	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,340,535 B1	03-2008	Alam, Naveed	709/246
*	B	US-7,042,848 B2	05-2006	Santiago et al.	370/253
*	C	US-2002/0103925 A1	08-2002	Sheth et al.	709/236
*	D	US-6,381,242 B1	04-2002	Maher et al.	370/394
*	E	US-2002/0163935 A1	11-2002	Paatela et al.	370/466
*	F	US-7,006,438 B2	02-2006	West et al.	370/231
*	G	US-2005/0149633 A1	07-2005	Natarajan et al.	709/238
*	H	US-2006/0034292 A1	02-2006	Wakayama et al.	370/395.5
*	I	US-2003/0185220 A1	10-2003	Valenci, Moshe	370/398
*	J	US-2003/0126286 A1	07-2003	Lee, Ki Young	709/238
*	K	US-6,650,644 B1	11-2003	Colley et al.	370/395.21
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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